Characterization and Testbeam Analysis of irradiated Silicon n-in-p Pixel Detectors for the ATLAS Upgrade

Christian Gallrapp¹
M. Beimforde², A. La Rosa¹, A. Macchiolo², R. Nisius²,
H. Pernegger¹, R. H. Richter³, P. Weigell²

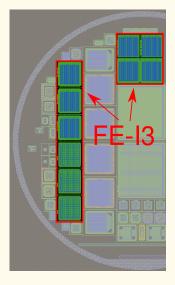
¹CERN-PH ²Max-Planck-Institut für Physik ³MPI-Halbleiterlabor

17th RD50 Workshop CERN - November 2010

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CiS-Production (n-in-p Batch)



Production within RD50 Collaboration & ATLAS Planar Pixel Sensor Group

Technology

18 Fz n-in-p wafers, 300 μm thick delivered by CiS.

Advantages

Single-sided process ⇒ Simpler and less expensive Structures

10 FE-I3: Single Chip Assembly (SCA) with different guard-ring (GR) and isolation schemes

HV stability

No sparks up to 700 V due to BCB (Benzo Cyclo Butene) passivation

DAQ-Systems

TurboDAQ setup



- TPLL and TPCC, VME based
- ATLAS FE-I3

USBPix setup

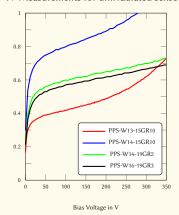


- USB based
- ATLAS FE-I3 and FE-I4

IV-Analysis

Leakage Current in µA

IV-Measurements for unirradiated sensors

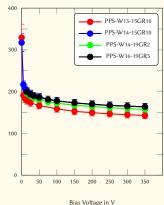


- Suggested working point for unirradiated sensors:
 - Bias voltage 150 V

Threshold-Tuning

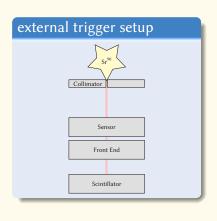
Noise in e-



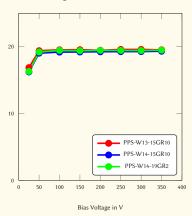


- Noise behavior is consistent with theory
- FE-noise is ~130 e[−]
 - Sensor noise @ $150 \text{ V} = \sim 40 \text{ e}^-$

Sr90 Mesurements



Charge distribution for CS2



- Theoretical values for 285 μm Silicon:
 - Qmean ~30.7 ke
 - Q_{MPV} ~21.9 ke⁻

Irradiation

Finished irradiation:

- CERN protons at $24 \, \text{GeV}$ 1 sensor at $\sim 6.2 \times 10^{14} \, n_{eq} / \text{cm}^2$ 1 SCA at $\sim 2 \times 10^{15} \, n_{eq} / \text{cm}^2$ 1 sensor at $\sim 2.5 \times 10^{15} \, n_{eq} / \text{cm}^2$ 1 SCA at $\sim 2.5 \times 10^{15} \, n_{eq} / \text{cm}^2$ 1 SCA at $\sim 3 \times 10^{15} \, n_{eq} / \text{cm}^2$ 1 sensor at $\sim 4.4 \times 10^{15} \, n_{eq} / \text{cm}^2$ SCA cooling down
- Karlsruhe protons at 25 MeV 1 SCA at $1 \times 10^{15} \, n_{eq}/cm^2$
- Ljubljana neutrons 1 SCA at 1×10¹⁵ n/cm²

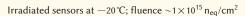
Upcoming irradiation:

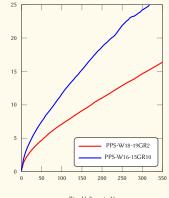
- Karlsruhe protons at 25 MeV
 1 SCA at 3×10¹⁵ n_{eq}/cm²
 1 SCA at 5×10¹⁵ n_{eq}/cm²
- Ljubljana neutrons 1 SCA at 3×10^{15} n/cm² 1 SCA at 5×10^{15} n/cm²

thanks to M. Glaser for the irradiation at CERN thanks to A. Dierlam and the Helmholtz Alliance for the irradiation in Karlsruhe thanks to V. Cindro for the irradiation in Ljubljana

IV-Analysis

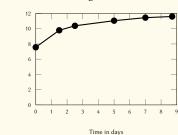
Leakage Current in µA





Bias Voltage in V

Annealing of W16-15GR10



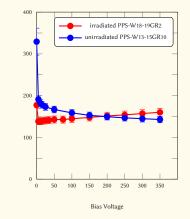
P. Weigell et al. / 8th International Conference on Radiation Effects on Semiconductor Materials Detectors and Devices, Florence October 2010

The calculated damage rate α is within the expected range

Collected Charge in ke-

Noise-Analysis

Noise for irradiated and unirradiated sensors

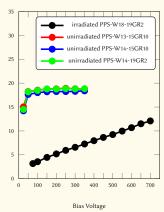


- PPS-W18-19GR2 was neutron irradiated up to 1×10¹⁵ n/cm² in Ljubljana
- Noise for irradiated sensors is increasing with higher bias voltage

Sr90 Mesurements

2MPV in ke-

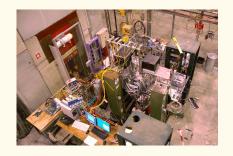
Charge distribution for CS1



- Sufficient charge collection after irradiation
- Increasing charge collection for higher bias voltages
- ~65% of charge collection at 700 V bias voltage compared to unirradiated sensors

Test-Beam Setup

- SPS beamline (H6) with 200 MeV pions
- 6 weeks of beam in 3 periodes
- several samples from different groups
- 6 samples from Munich



Testbeam-Group July 2010:

M. Benoit, Ch. Gallrapp, M. George, S. Grinstein, Z. Janoska, J. Jentsch, A. La Rosa,
S. Libov, D. Muenstermann, G. Piacquadio, B. Ristic, I. Rubinsky, A. Rummler,
D. Sutherland, G. Troska, S. Tsiskaridze, P. Weigell, J. Weingarten, T. Wittig

Test-Beam Setup

- EUDET-Telescope with ~4 μm resolution
- Test Beam Analysis
 - Matched clusters
 - All cluster sizes

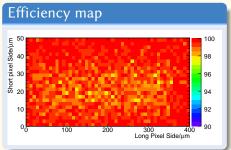


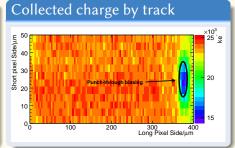
Testbeam-Group October 2010:

M. Beimforde, M. Benoit, M. Bomben, G. Calderini, Ch. Gallrapp, M. George, S. Gibson, S. Grinstein, Z. Janoska, J. Jentzsch, O. Jinnouchi, T. Kishida, A. La Rosa, V. Libov, A. Macchiolo, G. Marchiori, D. Muenstermann, R. Nagai, G. Piacquadio, B. Ristic, I. Rubinskiy, A. Rummler, Y. Takubo, G. Troska, S. Tsiskaridze, I. Tsurin, Y. Unno, P. Weigell, J. Weingarten, T. Wittig

Test-Beam Results - Unirradiated Sensors

 High efficiency for unirradiated sensor: ε = 99.31% Good charge collection, also in the punch-through region well above threshold



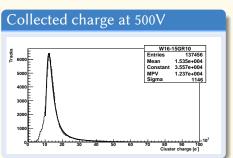


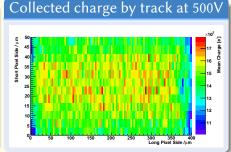
Preliminary TB results

Test-Beam Results - Proton Irradiated Sensor 10¹⁵n_{eq}/cm²

 Collected charge is in aggreement with lab-measurements

 Good charge collection in the whole sensor area

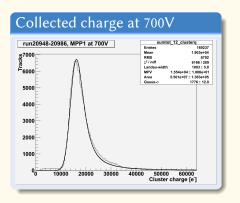




Preliminary TB results

Test-Beam Results - Neutron Irradiated Sensor 10¹⁵n_{eq}/cm²

- stable performace for several days at 700 V
- Good charge collection well above threshold



Preliminary TB results

Summary

Results

- Good threshold to noise ratio
- Good performance for irradiated sensors with Sr⁹⁰
- First promissing test-beam results for irradiated sensors
- HV-Stability up to 700 V

Plans

- Show HV stability for higher voltages needed for IBL fluences
- Measurements on higher irradiated sensors

Thank you for the attention! Questions?